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LTR	DESCRIPTION									DAT	E (Y	1- <b>M</b> O-	DA)	APPROVED												
А	Add figure 3. Technical changes in 1.3, 1.4, and tables I and II. Change in terminal connections. Editorial changes throughout.									8	9 A	UG 2	8		10	Ny S										
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DRAWING					APPROVED BY						1	MICROCIRCUIT, D MONOLITHIC SIL			T, DI SILI	DIGITAL, ECL, BINARY COUNTER										
FOR USE 6	THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE				DRAWING APPROVAL CATE  11 MARCH 1988							A 67268 5962-875			590	)										
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DESC FORM 193 SEP 87

\* U.S. GOVERNMENT PRINTING OFFICE: 1987 — 748-129/60911 5962-E1106

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

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1. SCOPE			••••	. • •	and the state of t		
1.1 Scope. with 1.2.1 of non-JAN device	This drawing desc MIL-STD-883, "Proves".	ribes devi	ce require the use o	ements of MIL	fer class B m -STD-883 in co	icrocircui	ts in accordance with compliant
1.2 Part n	umber. The complet	te part num	ber shall	be as	shown in the	following (	example:
<u>5</u>	962-87590	01			<u>E</u>		X 
וֹס	rawing number	Device (1.2.	type 1)	C	ase outline (1.2.2)		finish per IL-M-38510
1.2.1 <u>Devi</u>	ce type. The device	e type sha	11 identii	fy the	circuit funct	ion as foll	lows:
<u>De</u>	vice type G	ieneric num	ber	<u>c</u>	ircuit functio	<u>n</u>	
	01	10H416		4.	-bit binary co	unter	
1.2.2 <u>Case</u> as follows:	outlines. The cas	e outlines	shall be	as de:	signated in ap	pendix C of	F MIL-M-38510, and
Outli	ne letter		9	ase o	utline		
E F	<u>.</u> 2	D-2 (16-le F-5 (16-le C-2 (20-te	ad, .840" ad, .440" rminal, .3	x .310 x .28! 358" x	0" x .200"), d 5" x .085"), f .358" x .100"	ual-in-line lat package ), square c	e package e chip carrier package
	te maximum ratings.						
Junction Maximum	voltage range (Y <sub>EE</sub> ) oltage range – – temperature range aperature (solderin temperature (T <sub>J</sub> )- power dissipation resistance, juncti	(P <sub>D</sub> )		 	· +165 C · 718 mW		
1.4 Recomme	nded operating con	ditions.					
Ambient	operating temperat	ure range	(Ta)		+1.98 V   -55°C +0 +	dc to +2.02	-4.94 V dc maximum dc or V dc
TA = -	high level input v 25 C 125 C 55 C low level input vo				-0.780 V de -0.650 V de -0.840 V de -1.950 V de	C	
				Jan			port.
						• • •	
	ANDARDIZED	,	SIŻE A		e <b>te</b> de la companya		60.07500
	ARY DRAWING LECTRONICS SUPPLY O			L	REVISION LEVEL		62-87590
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## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

**MILITARY** 

MIL-M-38510

- Microcircuits, General Specification for.

**STANDARD** 

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
  - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth tables. The truth tables shall be as specified on figure 2.
- 3.2.3 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 3.
  - 3.2.4 Case outlines. The case outlines small be in accordance with 1.2.2 merein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements nerein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 nerein) shall be provided with each lot of microcircuits delivered to this drawing.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-87590			
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444			REVISION LEVEL	Α	SHEET 3	

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± U. S. GOVERNMENT PRINTING OFFICE: 1988—550-547

Electrical performance characteristics. Conditions  $-55^{\circ}C \le T_A \le +125^{\circ}C$  Unless otherwise specified Limits Unit Symbol Group A Test subgroups Min Max Quiescent tests 1/ Cases E, F, and 2 ٧<sub>IH</sub> V<sub>IL</sub> Outputs |-1.010|-0.780| |-0.860|-0.650 |-1.060|-0.840| -1.950 terminated -0.780 -1.950 -1.950 23 -0.650 -0.840 ٧ through  $100\Omega$  to -2 V High level output voltage VOH V<sub>CC</sub> = 0.0 V V<sub>EE</sub> = -5.2 V 27 -0.780 | -1.950 1 |-1.950|-1.580| |-1.950|-1.565| |-1.950|-1.610| -0.650 -0.840 -1.950 -1.950 ٧ Low level output voltage VOL -1.010 -0.780 High level threshold output VOHA -1.110 -1.480 -1.465 1-0.860|-0.650| -0.960 voltage |-1.060|-0.840| -1.510 3 -1.160 |-1.950|-1.580 |-1.950|-1.565 -1.480 -1.465 Low level threshold output voltage |-1.110 | |-0.960 | VOLA -1.950|-1.610| -1.160 -1.510  $V_{EE} = -5.46 \text{ V}$ -115 -126 mΑ Power supply drain current | IEE | VEE = -0.70 | VCC = 0.0 V | VIH = -0.780 V at +25°C | -0.650 V at +125°C -0.840 V at -55°C 1,2 700 Master reset μА High level input current I<sub>TH1</sub> 1190 265 450 All other I IH2 inputs VEE = -4.94 V ÌΙΙL 3/ 1,3 0.5 μΑ Low level input current  $V_{CC} = 0.0 \text{ V}$ 0.3  $V_{IL}^{55} = -1.950 \text{ V}$ Functional tests See 4.3.1c 7,8 See footnotes at end of table. SIZE **STANDARDIZED** Α 5962-87590 **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER **REVISION LEVEL** SHEET DAYTON, OHIO 45444

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**☆ U. B. GOVERNMENT PRINTING OFFICE: 1988—549-804** 

TABLE I. Electrical performance characteristics - Continued. Test Symbol Conditions Group A Limits Unit -55°C < TA < +125°C Unless otherwise specified subgroups Min Max Cases E and F DC rapid tests 4/ VIH VIL Outputs |-1.037|-0.810| |-0.890|-0.682| terminated I-0.810 i -1.950 i v<sub>oh</sub> High level output voltage through I-0.682 | -1.950 2 ٧ 1100Ω to -2 V 1-0.872 | -1.950 1-1.090|-0.872| V<sub>CC</sub> = 0.0 V V<sub>EE</sub> = -5.2 V -0.810 | -1.950 1 1-1.9501-1.5891 -1.950 -1.950 -1.950|-1.575| |-1.950|-1.620| Low level output voltage -0.682 -0.872 VOL 2 ٧ High level threshold output | VOHA |-1.137 |-0.990 -1.489 -1.475 |-1.037|-0.810| |-0.890|-0.682| 12 voltage ٧ 1-1.190 -1.520 3 1-1.0901-0.8721 Low level threshold output | YOLA -1.137 -1.489 1 2 I-1.950|-1.589| voltage |-0.990 | -1.475 1-1.950|-1.575| ٧ -1.520 |-1.190 | 3 |-1.950|-1.620| Power supply drain current | IEE VEE = -5.46 V VCC = 0.0 V VIH = -0.810 V at +25°C -0.682 V at +125°C -0.872 V at -55°C -114 -125 1 2,3 mΑ 3/ High level input current Master reset 1,2 I IH1 685  $\mu$ **A** 1175 250 435 All other I<sub>IH2</sub> 1,2 inputs Low level input current VEE = -4.94 V IIL 3/ 0.5 μА VCC = 0.0 V 0.3  $|V_{IL}^{00}| = -1.950 V$ Functional tests See 4.3.1c 7,8 See footnotes at end of table. **STANDARDIZED** SIZE Α 5962-87590 **MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER REVISION LEVEL** SHEET DAYTON, OHIO 45444 5

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± U. S. GOVERNMENT PRINTING OFFICE: 1988—549-904

TABLE I. Electrical performance characteristics - Continued. Limits Unit Conditions Group A Test Symbol -55°C < TA < +125°C Unless otherwise specified subgroups Min Max DC rapid tests 4/ Case 2 ٧IL VIH Outputs |-1.037|-0.809| |-0.889|-0.682| | terminated -0.809 -1.950 1 2 -1,950 ٧ Į V<sub>OH</sub> -0.682 High level output voltage through |-1.089|-0.872| |100Ω to -2 V 1-0.872 -1.950 V<sub>CC</sub> = 0.0 V V<sub>EE</sub> = -5.2 V |-1.950|-1.589| -1.950 -0.809 1 |-1.950|-1.575| |-1.950|-1.620| -1.950 -1.950 ٧ -0.682 2 Low level output voltage VOL -0.872 i-1.037i-0.809i -1.489 High level threshold output -1.137 1 |-0.889|-0.682| |-1.089|-0.872| VOHA -0.989 -1.475 ٧ voltage -1.189 -1.520 1-1.137 -1.4891 2 3 -1.950|-1.589 Low level threshold output -1.475 -1.520 |-1.950|-1.575 |-1.950|-1.620 -0.989 ٧ VOLA voltage -1.189 VEE = -5.46 V VCC = 0.0 V VIH = -0.809 V at +25°C -0.682 V at +125°C -114 -125 mΑ 1 2,3 Power supply drain current IEE 3/ -0.872 V at -55°C 1,2 685 μА Master reset High level input current I<sub>IH1</sub> 1175 250 435 All other 1,2 I<sub>IH2</sub> inputs  $\mu \boldsymbol{A}$ VEE = -4.94 V 0.5 ΊΙL 1,3 Low level input current 3/ VCC = 0.0 V 0.3  $V_{IL} = -1.950 V$ See 4.3.1c 7.8 Functional tests See footnotes at end of table. SIZE STANDARDIZED A 5962-87590 **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER **REVISION LEVEL** SHEET DAYTON, OHIO 45444 6

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**★** U. S. GOVERNMENT PRINTING OFFICE: 1988—548-90

	T		<del></del> -	T		T	
Test	Symbo?	Conditions	Group A	<u>L1</u>	Unit		
		-55°C < T <sub>A</sub> < +125°C   Unless otherwise specified	subgroups   	   Min 	Max	   	
Cases E, F, and 2		AC tests		<del></del>	· <u>· · · · · · · · · · · · · · · · · · ·</u>	<u> </u>	
Transition time	t <sub>TLH</sub> ,	V <sub>EE</sub> = -2.94 V   V <sub>CC</sub> = +2.0 V   C <sub>L</sub> < 5 pF	9   10   11	0.5	2.1 2.2 2.0	ns	
Propagation delay time, CP to Q, CP to TC, and MR to Q	t <sub>PLH</sub>	R = 100Ω  See figure 3     	9   10   11	   0.7   0.7   0.7	2.6   2.9   2.5	ns	
	tpHL		9 10 11	0.7 0.7 0.7	2.6 2.9 2.5	ns	
Maximum clock frequency	FMAX	 	9 10 11	200 200 200	]     	MHz	

- The quiescent limits are determined after a device has reached thermal equilibrium. This is defined as the reading taken with the device in a socket with > 500 LFPM of +25°C, +125°C, or -55°C (as applicable) air blowing on the unit in a transverse direction with power applied for at least 4 minutes before the reading is taken. This method was used for theoretical limit establishment only. All devices shall be tested to the delta V (rapid test) conditions specified herein. The rapid test method is an equivalent method of testing quiescent conditions.
- The high and low level output current varies with temperature, and shall be calculated using the following formula:  $I_{OH}$  = ( $V_{OH}$  2 V)/100 $\Omega$ ,  $I_{OL}$  = ( $V_{OL}$  2 V)/100 $\Omega$ .
- The  $I_{\mbox{\scriptsize FE}}$  and  $I_{\mbox{\scriptsize IL}}$  limits, although specified in the minimum column, shall not be exceeded, in magnitude, as a maximum value.
- The dc rapid test forcing functions and limits are used for all dc testing. These limits are determined for each device type based on the power dissipation and package type. The rapid test (delta V) limits and forcing functions are skewed allowing rapid testing to be performed at standard temperatures without the addition of delta T's.

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- 3.7 Notification of change. Notification of cnange to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method 1015 of MIL-STD-883.
    - (1) Test condition D or E using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125$ °C, minimum.
  - b. Interim and final electrical test parameters snall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Supgroups 7 and 8 tests shall verify the truth table specified on figure 2 herein.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
      - Test condition D or E using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125$ °C, minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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Case outlines	E	F	2			
Terminal number	   Terminal symbol					
1	V <sub>CC1</sub>	CP	l NC			
2	Q1	Q3	V <sub>CC1</sub>			
3	Q0	Q2	Q1			
4	TC	V <sub>CC2</sub>	QO			
5	PE	V <sub>CC1</sub>	TC			
6	CE	Q1	NC			
7	PO	00	PE			
8	VEE	TC	CE			
9	P1	PE	PO PO			
10	P2	CE	V <sub>EE</sub>			
11	Р3	PO	NC NC			
12	MR	VEE	P1			
13	СР	P1	P2			
14	Q3	P2	Р3			
15	Q2	Р3	MR			
16	V <sub>CC2</sub>	MR	NC			
17			CP			
18			Q3			
19			Q2			
20		 	V <sub>CC2</sub>			

NC = No connection

FIGURE 1. Terminal connections.

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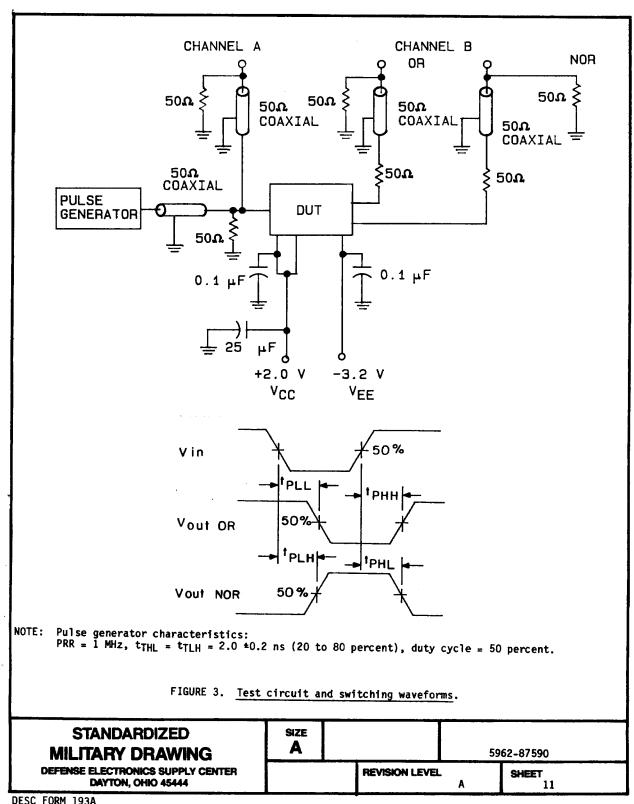
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**Synchronous** counting sequence PE = H, CE = L Q2 | Q3 TC Q0 Q1 Н H Н Н L L L Н Н Ł Н Н Н Н H Н Н Н Н Н Н Н Н Н PE = L Output at Qt + 1 Parallel input | PO, P1, P2, P3 | Q0, Q1, Q2, Q3 L H Н Mode of PE CE operation Parallel Н Load Count Н L Hold Count MR Output Q See tables above H = High voltage level L = Low voltage level FIGURE 2. Truth tables. SIZE **STANDARDIZED** Α 5962-87590 **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 REVISION LEVEL SHEET

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups   (per method   5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 7*, 8, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

<sup>\*</sup> PDA applies to subgroups 1 and 7.

## 5. PACKAGING

 $5.1\,$  Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor   CAGE   number	Vendor   similar part   number <u>1</u> /
5962-8759001EX	04713	10H416/BEAJC
5962-8759001FX	04713	10H416/BFAJC
5962-87590012X	04713	10H416M/B2AJC

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

04/13

Vendor name and address

Motorola, Incorporated 7402 South Price Road Tempe, AZ 85283

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